

SCI Test Capabilities

- In-Circuit & Functional-test
- Testing for Printed Circuit Board Assembly (PCBA)
- Automated Optical Inspection (AOI), Hi-Pot
- Flying Probe
- Qualification Testing
 - Mil-Std-810, RTCA/DO-160 (Commercial Aviation) Requirements
 - Temperature, Temperature Shock, Temperature and Altitude, Humidity, Vibration, Shock, Gunfire Shock, Crash Safety, Acceleration, Immersion, Waterproofness, HALT/HASS
 - MIL-STD-461 EMI Requirements
 - Conducted Emissions, Conducted Susceptibility, Radiated Emissions, Radiated Susceptibility
- Environment Stress Screening (ESS)
 - 29 chambers, 30 Degree C / Min ramp
 - -73C to +177C
 - 8 chambers w/ vibration tables (single axis, random vibration to 6,000 f-lbs, sine to 5,400 f-lbs)
 - Humidity chamber (from -20C to +177C at 95% RH)
- Vibration
 - Up to 15,000 force lbs.
 - Velocities up to 70 in/sec
 - Frequencies: 5 to 3kHz
 - Displacement up to 2.5 inches
 - Armatures size up to 33.5 inches
 - Random, Sine, Sine on Random, Random on Random
- Highly Accelerated Life Test (HALT)/Highly Accelerated Stress Screening (HASS)
 - Qualmark TYPHOON 4
 - 70°C/minute ramp rate
 - -100°C to +200°C temp range
 - 50 Grms from 2 to 10 kHz
 - Thermotron AST-35-LN2
 - 70°C/minute ramp rate
 - -100°C to +200°C temp range
 - 50 Grms from 2 to 10 kHz
 - 29" x 29 " platform
- EMI
 - Conducted Emissions
 - Power Line
 - Conducted Susceptibility
 - Power Line, Modulated, Transient
 - Radiated Emissions
 - Magnetic Field, Electric Field
 - Radiated Susceptibility
 - Magnetic Field Electro-Magnetic Interference (excluding 200 V/M and Lightning)
- Failure Analysis
 - SEM/EDS (Scanning Electron Microscopy/Energy Dispersive Spectroscopy) — Cambridge S200 and PGT IMIX
 - High power microscopy (Zeiss Universal) — upright / bright-field, DIC, hotspot detection to x1024

- Digital capabilities for macro- and micro-imaging (including Canon A620 camera)
- InterTest 1014 Leak Test Pressurization System
- Varian 938-41 Fine leak (helium) detector
- LFE plasma systems 104 Barrel plasma etch system
- Destructive Physical Analysis
- X-Ray
- X-Ray Florescent
- Electrical test
 - Curve Tracer
 - Scopes
 - Pulse/Function Generator
 - Counters
 - Impedance Analyzers
 - Hi-Pot Tester
- Particle Impact EM/Noise Detection